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Application/Control No.	Applicant(s)/Patent under Reexamination
10/769,684	BONILLA ET AL.
Examiner	Art Unit
Leon J. Harper	2166

	SEARCHED		
Class	Subclass	Date	Examiner
707	104.1,100, 10,1,5	9/7/2006	LJH
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR	NOT CH S	ES STRATEGY)
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